

the crystal lattice. To measure a powder pattern, a randomly oriented powdered sample is prepared in an effort to expose all the planes in the lattice. The scattering angle is determined by slowly rotating the sample and measuring the angle of diffracted X rays (typically using a scintillation detector) with respect to the angle of the incident beam. Alternatively, the angle between sample and source can be kept fixed, while moving the detector to determine the angles of the scattered radiation. Knowing the wavelength of the incident beam, the spacing between the planes (identified as the *d*-spacings) is calculated using Bragg's Law.

The XRD pattern will therefore consist of a series of peaks detected at characteristic scattering angles. These angles, and their relative intensities, can be correlated with the computed *d*-spacings to provide a full crystallographic characterization of the powdered sample. After indexing all the scattered lines, it is possible to derive unit cell dimensions from the powder pattern of the substance under analysis. For routine work, however, this latter analysis is not normally performed, and one typically compares the powder pattern of the analyte to that of reference materials to establish the polymorphic identity. Because every compound produces its own characteristic powder pattern owing to the unique crystal structure, powder XRD is clearly the most powerful and fundamental tool for polymorphic identity of an analyte.

The United States Pharmacopeia contains a general chapter on XRD (61), which sets the criterion that identity is established if the scattering angles in the powder patterns of the sample and reference standard agree to within the calibrated precision of the diffractometer. It is noted that it is generally sufficient that the scattering angles of the ten strongest reflections obtained for an analyte agree to within either ± 0.10 or $\pm 0.20^\circ 2\theta$, whichever is more appropriate for the diffractometer used. Older versions of the general test contained an additional criterion for relative intensities of the scattering peaks, but it has been noted that relative intensities may vary considerably from that of the reference standard, making it impossible to enforce a criterion based on the relative intensities of corresponding scattering peaks.

For identification purposes, it is usually convenient to identify the angles of the 10 most intense scattering peaks in a powder pattern, and to then list the accepted tolerance ranges of these based on the diffractometer used for the determinations. Useful tabulations of the XRD patterns of a number of compounds have been published by Koundourellis and coworkers, including 12 diuretics (62), 12 vasodilators (63), and 12 other commonly used drug substances (64).

The literature abounds with countless examples that illustrate how powder diffraction has been used to distinguish between polymorphs. It is safe to state that one could not publish the results of a phase characterization study without the inclusion of XRD data. Nowhere is this more crucial than in intellectual property controversies, where the different XRD patterns of polymorphs are used for patentability purposes. For example, two polymorphic forms of ibandronate sodium have been the subject of two United States patent applications (65), and although the XRD patterns of these are somewhat similar (Fig. 11), a sufficient number of differences in scattering peak angles exist so as to permit their identification. In the patent applications, some of the claims define the two polymorphs on the basis of five characteristic XRD scattering peaks, which enables one to tabulate the data and determine whether or not a given sample of ibandronate sodium is within the scope of these XRD claims.

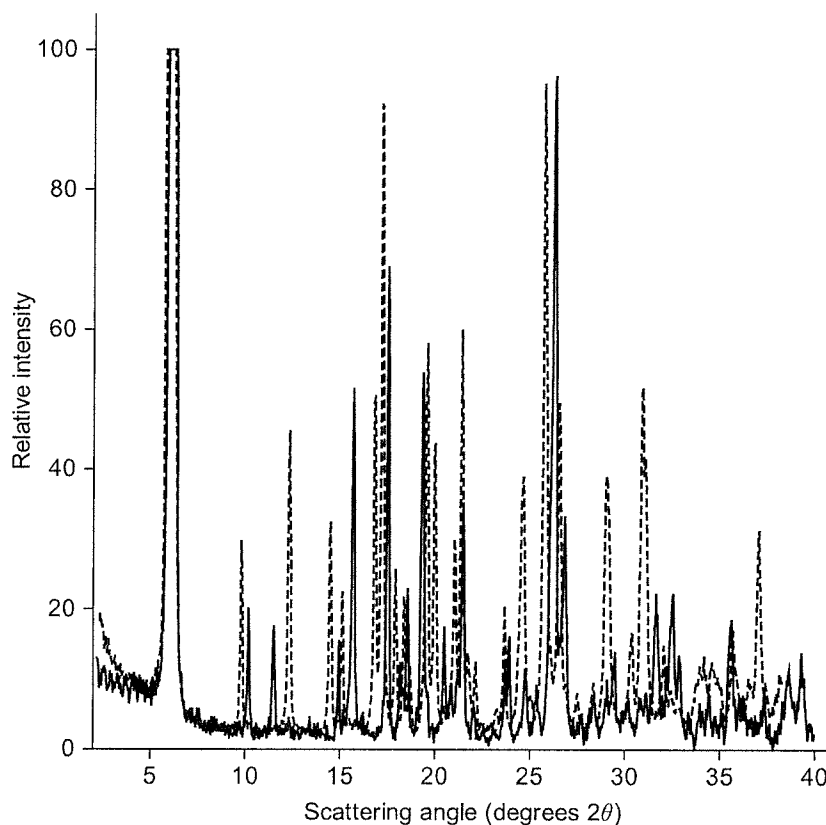


FIGURE 11 X-ray powder diffraction patterns of ibandronate sodium, Form A (*solid trace*) and Form B (*dashed trace*). The patterns have been adapted from data in United States patent applications 2006/0172975 and 2006/0172976 (65).

Once the characteristic XRD patterns of one or more analytes have been established, it is usually possible to develop methods for phase quantification. The methodology is based on the premise that each component will contribute to the overall scattering by an amount that is proportional to its weight fraction in a mixture, and that the powder pattern of each analyte contains one or more peaks whose scattering angle is unique to that analyte. Quantitative analysis typically requires the use of reference standards that contribute known scattering peaks at appropriate scattering intensities. This can be achieved through the use of internal standards, where one would mix reference materials such as elemental silicon or lithium fluoride into the sample matrix.

Although simple intensity correction techniques can be used to develop suitable quantitative XRD methods, the introduction of more sophisticated data acquisition and handling techniques can greatly improve the quality of the developed method. For instance, improvement of the powder pattern quality through use of the Rietveld method has been used to evaluate mixtures of two anhydrous polymorphs of carbamazepine and the dihydrate solvatomorph (66). The method of whole pattern analysis developed by Rietveld (67) has found widespread use in crystal structure refinement and in the quantitative analysis of complex mixtures.